· · · · · · · · · · · · · · · · · · ·	, <b>1</b> 5								71	•	4			
			ŚÌ	1ee	t <u>1</u>	of	1					al No.: 05,237		
	-	REF AF SED	PL	I C	TNA				Applicant: Michio OSADA et al.					
DATED	P 200		r	2,	20	02			U.S. Filing Date: November 2, 2000			Art Unit: 1732 1722		
U. S. PATENT DOCUMENTS														
*EXAMINER INITIAL		DOCUMENT NO.							DATE	NAME		cl.	Sub- Cl.	Fil. Date
			1									}	}	
FOREIGN PATENT DOCUMENTS  Trans.														
		DOCUMENT NO. DAT								COUNTRY	c1.	C1.	Yes	No
TN	AA	56	1	4	1	9	2	2	11/1981	Japan		_	x~ Abst.	
TN	АВ	10	2	0	2	6	9	8	08/1998	Japan 🗸		-	x- Abst.	
examiner hulchanh lguyn Date considered $\frac{RECEIVED}{CC7092002}$														
										T	200	7 <u>7</u>		
EXAMINER	Th	wel	lai	rh	No	μυ	yer		nsidered to	1700	)			
											_			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.